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| Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE | | | | | Atty. Docket No. GB 000180 | | Serial No. | | | | | | | | |
| | | | | | Applicant PAUL F. FEWSTER et al. | | | | | | | | | | |
| | | | | | Filing Date CONCURRENTLY | | Group | | | | | | | | |
| INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) | | | | | | | | | | | | | | | |
| U.S. PATENT DOCUMENTS | | | | | | | | | | | | | | | |
| Ex. Int. | | Document Number | | | | | | Date | Name | Class | Sub- class | Filing Date If Approp. | | | |
| | AA | | | | | | | | | | | | | | |
| | AB | | | | | | | | | | | | | | |
| | AC | | | | | | | | | | | | | | |
| | AD | | | | | | | | | | | | | | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | | | | | | | | | |
| | | Document Number | | | | | | Date | Country | Class | Sub- class | Trans. | | | |
| | | | | | | | | | | | | | Yes | No | |
| ACH | AG | 0 | 3 | 1 | 8 | 0 | 1 | 2 | A | 2 | 5/31/89 | EUROPE | G01N | 23/207 | X |
| ACH | AH | A | 0 | 1 | 2 | 7 | 0 | 6 | 5 | 0 | 10/27/89 | Japan (Abstract) | G01N | 23/207 | X |
| ACH | AI | A | 0 | 1 | 2 | 7 | 6 | 0 | 5 | 2 | 11/6/89 | Japan (Abstract) | G01N | 23/207 | X |
| | AJ | | | | | | | | | | | | | | |
| | AK | | | | | | | | | | | | | | |
| OTHER (Including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | | | | | | | | | |
| ACH | AL | "Characterization of Thin Layers on Perfect Crystals with a Multipurpose High Resolution X-ray Diffractometer", Bartels, Journal Vacuum Science and Technology B Volume 1 page 338 (1983). | | | | | | | | | | | | | |
| | AM | | | | | | | | | | | | | | |
| | AN | | | | | | | | | | | | | | |
| Examiner <i>Allen C. Ho</i> | | | | | Date Considered <i>19 Oct 2004</i> | | | | | | | | | | |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant. | | | | | | | | | | | | | | | |

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|--|----|--------------------|---|---|---|---|---|---|------------|--------------------------------------|---------|--------------------------|---------------|---------------------------|----|--|
| INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) | | | | | | | | | | Applicant Paul P. Fewster, et.al. | | | | | | |
| | | | | | | | | | | Filing Date December 13, 2001 | | Group 2882 | | | | |
| U.S. PATENT DOCUMENTS | | | | | | | | | | | | | | | | |
| Ex. Int | | Document Number | | | | | | | | Date | Name | Class | Sub- class | Filing Date If Approp. | | |
| ACH | AA | 5 | 8 | 5 | 0 | 4 | 2 | 5 | 12/15/1998 | Wilkins | 378 | 85 | | | | |
| ACH | AB | 5 | 8 | 7 | 8 | 1 | 0 | 6 | 3/2/1999 | Fujiwara | 378 | 79 | | | | |
| | AC | | | | | | | | | | | | | | | |
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| Examiner <u>Allen C Ho</u> | | | | | | | | | | Date Considered <u>19 Oct. 2004</u> | | | | | | |
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